

3.3 V ECL/PECL/HSTL/LVDS ÷2/4, ÷4/6 Clock Generation Chip

MC100ES6039

The MC100ES6039 is a low skew $\div 2/4$, $\div 4/6$ clock generation chip designed explicitly for low skew clock generation applications. The internal dividers are synchronous to each other, therefore, the common output edges are all precisely aligned. The device can be driven by either a differential or single-ended ECL or, if positive power supplies are used, LVPECL input signals. In addition, by using the V_{BB} output, a sinusoidal source can be AC coupled into the device.

The common enable $\overline{(EN)}$ is synchronous so that the internal dividers will only be enabled/disabled when the internal clock is already in the LOW state. This avoids any chance of generating a runt clock pulse on the internal clock when the device is enabled/disabled as can happen with an asynchronous control. The internal enable flip-flop is clocked on the falling edge of the input clock, therefore, all associated specification limits are referenced to the negative edge of the clock input.

Upon startup, the internal flip-flops will attain a random state; therefore, for systems which utilize multiple ES6039s, the master reset (MR) input must be asserted to ensure synchronization. For systems which only use one ES6039, the MR pin need not be exercised as the internal divider design ensures synchronization between the $\div 2/4$ and the $\div 4/6$ outputs of a single device. All V $_{\rm CC}$ and V $_{\rm EE}$ pins must be externally connected to power supply to guarantee proper operation.

The 100ES Series contains temperature compensation.

Features

- Maximum Frequency >1.0 GHz Typical
- 50 ps Output-to-Output Skew
- PECL Mode Operating Range: V_{CC} = 3.135 V to 3.8 V with V_{EE} = 0 V
- ECL Mode Operating Range: V_{CC} = 0 V with V_{EE} = -3.135 V to -3.8 V
- · Open Input Default State
- · Synchronous Enable/Disable
- Master Reset for Synchronization of Multiple Chips
- V_{BB} Output
- LVDS and HSTL Input Compatible
- 20-Lead Pb-Free Package Available

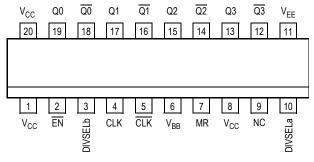


DW SUFFIX
20-LEAD SOIC PACKAGE
CASE 751D-07



EG SUFFIX 20-LEAD TSSOP PACKAGE Pb-FREE PACKAGE CASE 751D-07

ORDERING INFORMATION					
Device	Package				
MC100ES6039DW	SO-20				
MC100ES6039DWR2	SO-20				
MC100ES6039EG	SO-20 (Pb-Free)				
MC100ES6039EGR2	SO-20 (Pb-Free)				



Warning: All V_{CC} and V_{EE} pins must be externally connected to Power Supply to guarantee proper operation.

Figure 1. 20-Lead Pinout (Top View)

Table 1. Pin Description

Pin	Function
$CLK^{(1)}, \overline{CLK}^{(1)}$	ECL Diff Clock Inputs
EN ⁽¹⁾	ECL Sync Enable
MR ⁽¹⁾	ECL Master Reset
V_{BB}	ECL Reference Output
Q0, Q1, Q0, Q1	ECL Diff ÷2/4 Outputs
Q2, Q3, Q2, Q3	ECL Diff ÷4/6 Outputs
DIVSELa ⁽¹⁾	ECL Freq. Select Input ÷2/4
DIVSELb ⁽¹⁾	ECL Freq. Select Input ÷4/6
V _{CC}	ECL Positive Supply
V _{EE}	ECL Negative Supply
NC	No Connect

1. Pins will default low when left open.

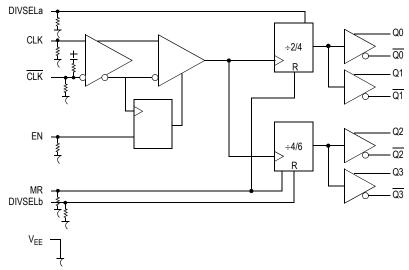


Figure 2. Logic Diagram

Table 2. Function Tables

CLK	EN	MR	Function
Z	L	L	Divide
ZZ	Н	L	Hold Q0:3
X	X	Н	Reset Q0:3

X = Don't Care

Z = Low-to-High Transition

ZZ = High-to-Low Transition

DIVSELa	Q0:1 Outputs
L	Divide by 2
H	Divide by 4
DIVSELb	Q2:3 Outputs
L	Divide by 4
H	Divide by 6

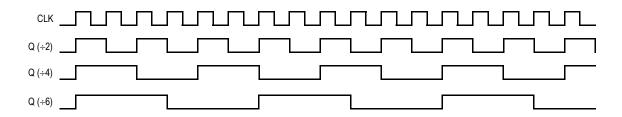


Figure 3. Timing Diagram

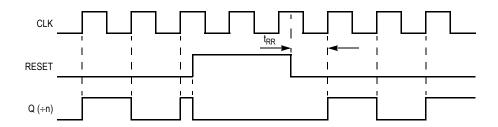


Figure 4. Timing Diagram

Table 3. Attributes

Characteristics		Value
ternal Input Pulldown Resistor		75 kΩ
Internal Input Pullup Resistor	75 kΩ	
ESD Protection	Human Body Model Machine Model Charged Device Model	> 4 kV > 200 V > 2 kV

Meets or exceeds JEDEC Spec EIA/JESD78 IC Latchup Test

Table 4. Maximum Ratings⁽¹⁾

Symbol	Parameter	Condition 1	Condition 2	Rating	Units
V _{CC}	PECL Mode Power Supply	V _{EE} = 0 V		3.9	V
V _{EE}	ECL Mode Power Supply	V _{CC} = 0 V		-3.9	V
VI	PECL Mode Input Voltage ECL Mode Input Voltage	V _{EE} = 0 V V _{CC} = 0 V	$\begin{aligned} &V_I \leq V_{CC} \\ &V_I \geq V_{EE} \end{aligned}$	3.9 -3.9	V V
l _{out}	Output Current	Continuous Surge		50 100	mA mA
I _{BB}	V _{BB} Sink/Source			± 0.5	mA
T _A	Operating Temperature Range			-40 to +85	°C
T _{stg}	Storage Temperature Range			-65 to +150	°C
θ_{JA}	Thermal Resistance (Junction-to-Ambient)	0 LFPM 500 LFPM	20 SOIC 20 SOIC	TBD TBD	°C/W

^{1.} Maximum Ratings are those values beyond which device damage may occur.

Table 5. DC Characteristics ($V_{CC} = 0 \text{ V}, V_{EE} = -3.8 \text{ V} \text{ to } -3.135 \text{ V} \text{ or } V_{CC} = 3.135 \text{ V} \text{ to } 3.8 \text{ V}, V_{EE} = 0 \text{ V})^{(1)}$

Symbol	Characteristic	−40°C			0°C to 85°C			Unit
Syllibol	Characteristic	Min	Тур	Max	Min	Тур	Max	Oill
I _{EE}	Power Supply Current		35	60		35	60	mA
V _{OH}	Output HIGH Voltage ⁽²⁾	V _{CC} –1150	V _{CC} –1020	V _{CC} -800	V _{CC} –1200	V _{CC} –970	V _{CC} –750	mV
V _{OL}	Output LOW Voltage ⁽²⁾	V _{CC} –1950	V _{CC} –1620	V _{CC} –1250	V _{CC} –2000	V _{CC} –1680	V _{CC} –1300	mV
V _{IH}	Input HIGH Voltage (Single-Ended)	V _{CC} –1165		V _{CC} -880	V _{CC} -1165		V _{CC} -880	mV
V _{IL}	Input LOW Voltage (Single-Ended)	V _{CC} –1810		V _{CC} –1475	V _{CC} –1810		V _{CC} –1475	mV
V _{BB}	Output Reference Voltage	V _{CC} -1400		V _{CC} –1200	V _{CC} -1400		V _{CC} –1200	mV
V _{PP}	Differential Input Voltage ⁽³⁾	0.12		1.4	0.12		1.4	V
V_{CMR}	Differential Cross Point Voltage ⁽⁴⁾	V _{EE} +0.2		V _{CC} -0.7	V _{EE} +0.2		V _{CC} -0.7	V
I _{IH}	Input HIGH Current			150			150	μΑ
I _{IL}	Input LOW Current	0.5			0.5			μΑ

^{1.} MC100ES6139 circuits are designed to meet the DC specifications shown in the above table after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse airflow greater than 500 Ifpm is maintained.

^{2.} All loading with 50 Ω to V $_{\mbox{CC}}\mbox{--}2.0$ volts.

^{3.} V_{PP} (DC) is the minimum differential input voltage swing required to maintain device functionality.

^{4.} V_{CMR} (DC) is the crosspoint of the differential input signal. Functional operation is obtained when the crosspoint is within the V_{CMR} (DC) range and the input swing lies within the $V_{\mbox{\footnotesize{PP}}}$ (DC) specification.

	Table 6.	AC Characteristics	$(V_{CC} = 0 \ V. \ V_{EE} = 0)$	–3.8 V to –3.135 V or V _{CC} = 3.135	$V \text{ to } 3.8 \text{ V. } V_{EE} = 0 \text{ V})^{(1)}$
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Symbol	Characte	riatio		-40°C			25°C			85°C		Unit
Symbol	Characteristic	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit	
f _{max}	Maximum Frequenc	у		> 1			> 1			> 1		GHz
t _{PLH} , t _{PHL}	Propagation Delay	CLK, Q (Diff) MR, Q	575 500		875 850	575 500		875 850	575 500		875 850	ps ps
t _{RR}	Reset Recovery		200	100		200	100		200	100		ps
t _s	Setup Time	EN, CLK DIVSEL, CLK	200 400	120 180		200 400	120 180		200 400	120 180		ps ps
t _h	Hold Time	CLK, EN CLK, DIVSEL	100 200	50 140		100 200	50 140		100 200	50 140		ps ps
t _{PW}	Minimum Pulse Wid	th MR	550	450		550	450		550	450		ps
t _{SKEW}	Within Device Skew Q, Q @ Sa Device-to-Device Sl	me Frequency			80 50 300			80 50 300			80 50 300	ps ps ps
t _{JITTER}	Cycle-to-Cycle Jitter	r (RMS 1σ)			1			1			1	ps
V _{PP}	Input Voltage Swing	(Differential)	150		1400	150		1400	150		1400	mV
V _{CMR}	Differential Cross Po	oint Voltage	V _{EE} +0.2		V _{CC} -1.1	V _{EE} +0.2		V _{CC} -1.1	V _{EE} +0.2		V _{CC} -1.1	V
t _r t _f	Output Rise/Fall Tin (20% – 80%)	nes Q, \overline{Q}	50		300	50		300	50		300	ps

- 1. Measured using a 750 mV source, 50% duty cycle clock source. All loading with 50 Ω to V_{CC} –2.0 V.
- 2. Skew is measured between outputs under identical transitions. Duty cycle skew is defined only for differential operation when the delays are measured from the cross point of the inputs to the cross point of the outputs.

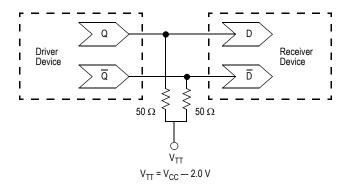
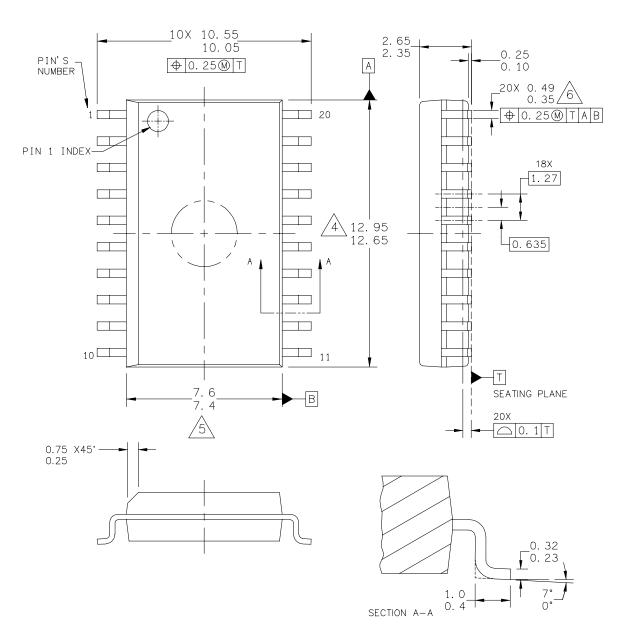


Figure 5. Typical Termination for Output Driver and Device Evaluation

PACKAGE DIMENSIONS



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TITLE:		DOCUMENT NO): 98ASB42343B	REV: J
20LD SOIC W/B, 1. CASF-OUTLI	CASE NUMBER: 751D-07 23 MAR 20			
CASE-001E1	STANDARD: JE	IDEC MS-013AC		

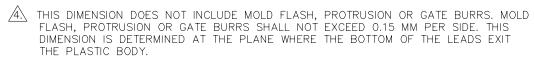
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CASE 751D-07 ISSUE J 20-LEAD SOIC PACKAGE

PACKAGE DIMENSIONS

NOTES:

- 1. DIMENSIONS ARE IN MILLIMETERS.
- 2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
- 3. DATUMS A AND B TO BE DETERMINED AT THE PLANE WHERE THE BOTTOM OF THE LEADS EXIT THE PLASTIC BODY.





6.	THIS DIMENSION DOES NOT INCLUDE	DAMBAR PROTRUSION.	ALLOWABLE DAMBAR PROTRUSION
	SHALL NOT CAUSE THE LEAD WIDTH	H TO EXCEED 0.62 mm.	

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20LD SOIC W/B, 1.2 CASE OUTLIN	CASE NUMBER: 751D-07 23 MAR 200			
CASE OUTEIN	STANDARD: JE	IDEC MS-013AC		

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CASE 751D-07 ISSUE J 20-LEAD SOIC PACKAGE

IDT™ 3.3 V ECL/PECL/HSTL/LVDS ÷2/4, ÷4/6 Clock Generation Chip

MC100ES6039

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www.IDT.com

For Sales

800-345-7015 408-284-8200 Fax: 408-284-2775

For Tech Support

netcom@idt.com 480-763-2056

Corporate Headquarters

Integrated Device Technology, Inc. 6024 Silver Creek Valley Road San Jose, CA 95138 United States 800 345 7015 +408 284 8200 (outside U.S.)

Asia Pacific and Japan

Integrated Device Technology Singapore (1997) Pte. Ltd. Reg. No. 199707558G 435 Orchard Road #20-03 Wisma Atria Singapore 238877 +65 6 887 5505

Europe

IDT Europe, Limited Prime House Barnett Wood Lane Leatherhead, Surrey United Kingdom KT22 7DE +44 1372 363 339



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